Product/Process Change Notice - PCN 17_0096 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: ADL5610 and ADL5611 Die Revision

Publication Date: 28-May-2017

Effectivity Date: 26-Aug-2017 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release

Description Of Change

1) Resistor value in bias circuit changed to increase transistor operating range.
2) Added Polyimide overcoat (PBO).

Reason For Change

1) Remove the potential for a supply current spike caused by slow power supply ramp up.
2) Increase moisture robustness and add scratch protection.

Impact of the change (positive or negative) on fit, form, function & reliability

No change to fit, form, function, or reliability and no change to the product data sheet.

Summary of Supporting Information

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

ADI_PCN_17_0096_Rev_-_Qual Result Summary_ADL5610_ADL5611.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.					
Americas:	PCN_Americas@analog.com	**Europe:**	PCN_Europe@analog.com	**Japan:**	PCN_Japan@analog.com
				Rest of Asia:	PCN_ROA@analog.com

Appendix A - Affected ADI Models				
Added Parts On This Revision - Product Family / Model Number (2)				
ADL5610 / ADL5610ARKZ-R7	ADL5611 / ADL5611ARKZ-R7			

Appendix B - Revision History			
Rev	**Publish Date**	**Effectivity Date**	**Rev Description**
Rev. -	28-May-2017	26-Aug-2017	Initial Release